



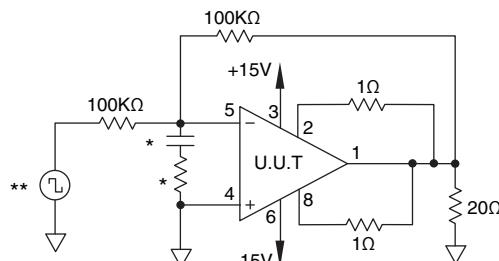
TABLE 4 GROUP A INSPECTION

PA73M/883

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SG	PARAMETER	SYMBOL	TEMP.	POWER	TEST CONDITIONS	MIN	MAX	UNITS
1	Quiescent Current	I_Q	25°C	±28V	$V_{IN} = 0, A_v = 100$		5	mA
1	Input Offset Voltage	V_{OS}	25°C	±28V	$V_{IN} = 0, A_v = 100$		±10	mV
1	Input Offset Voltage	V_{OS}	25°C	±10V	$V_{IN} = 0, A_v = 100$		±17.2	mV
1	Input Offset Voltage	V_{OS}	25°C	±30V	$V_{IN} = 0, A_v = 100$		±10.8	mV
1	Input Bias Voltage, +IN	$+I_B$	25°C	±28V	$V_{IN} = 0, A_v = 100$		±40	nA
1	Input Bias Current, -IN	$-I_B$	25°C	±28V	$V_{IN} = 0$		±40	nA
1	Input Offset Current	I_{OS}	25°C	±28V	$V_{IN} = 0$		±25	nA
3	Quiescent Current	I_Q	-55°C	±28V	$V_{IN} = 0, A_v = 100$		5	mA
3	Input Offset Voltage	V_{OS}	-55°C	±28V	$V_{IN} = 0, A_v = 100$		±15.2	mV
3	Input Offset Voltage	V_{OS}	-55°C	±10V	$V_{IN} = 0, A_v = 100$		±22.4	mV
3	Input Offset Voltage	V_{OS}	-55°C	±30V	$V_{IN} = 0, A_v = 100$		±16	mV
3	Input Bias Current, +IN	$+I_B$	-55°C	±28V	$V_{IN} = 0$		±72	nA
3	Input Bias Current, -IN	$-I_B$	-55°C	±28V	$V_{IN} = 0$		±72	nA
3	Input Offset Current	I_{OS}	-55°C	±28V	$V_{IN} = 0$		±60	nA
2	Quiescent Current	I_Q	125°C	±28V	$V_{IN} = 0, A_v = 100$		7	mA
2	Input Offset Voltage	V_{OS}	125°C	±28V	$V_{IN} = 0, A_v = 100$		±16.5	mV
2	Input Offset Voltage	V_{OS}	125°C	±10V	$V_{IN} = 0, A_v = 100$		±23.7	mV
2	Input Offset Voltage	V_{OS}	125°C	±30V	$V_{IN} = 0, A_v = 100$		±17.3	mV
2	Input Bias Current, +IN	$+I_B$	125°C	±28V	$V_{IN} = 0$		±80	nA
2	Input Bias Current, -IN	$-I_B$	125°C	±28V	$V_{IN} = 0$		±80	nA
2	Input Offset Current	I_{OS}	125°C	±28V	$V_{IN} = 0$		±80	nA
4	Output Voltage, $I_o = 5A$	V_o	25°C	±18.3V	$R_L = 2.07\Omega$	10.3		V
4	Output Voltage, $I_o = 50mA$	V_o	25°C	±30V	$R_L = 500\Omega$	25		V
4	Output Voltage, $I_o = 2A$	V_o	25°C	±30V	$R_L = 12\Omega$	24		V
4	Current Limits	I_{CL}	25°C	±18V	$R_L = 12\Omega, R_{CL} = 1\Omega$.54	.86	A
4	Stability/Noise	E_N	25°C	±28V	$R_L = 500\Omega, A_v = 1, C_L = 10nF$		1	mV
4	Slew Rate	SR	25°C	±28V	$R_L = 500\Omega$	1	10	V/us
4	Open Loop Gain	A_{OL}	25°C	±28V	$R_L = 500\Omega, F = 10Hz$	91		dB
4	Common Mode Rejection	CMR	25°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	70		dB
6	Output Voltage, $I_o = 5A$	V_o	-55°C	±18.3V	$R_L = 2.07\Omega$	10.3		V
6	Output Voltage, $I_o = 50mA$	V_o	-55°C	±30V	$R_L = 500\Omega$	25		V
6	Output Voltage, $I_o = 2A$	V_o	-55°C	±30V	$R_L = 12\Omega$	24		V
6	Stability/Noise	E_N	-55°C	±30V	$R_L = 500\Omega, A_v = 1, C_L = 10nF$		1	mV
6	Slew Rate	SR	-55°C	±28V	$R_L = 500\Omega$	1	10	V/us
6	Open Loop Gain	A_{OL}	-55°C	±28V	$R_L = 500\Omega, F = 10Hz$	91		dB
6	Common Mode Rejection	CMR	-55°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	70		dB
5	Output Voltage, $I_o = 3A$	V_o	125°C	±11.3V	$R_L = 2.07\Omega$	6.3		V
5	Output Voltage, $I_o = 50mA$	V_o	125°C	±30V	$R_L = 500\Omega$	25		V
5	Output Voltage, $I_o = 2A$	V_o	125°C	±30V	$R_L = 12\Omega$	24		V
5	Stability/Noise	E_N	125°C	±28V	$R_L = 500\Omega, A_v = 1, C_L = 10nF$		1	mV
5	Slew Rate	SR	125°C	±28V	$R_L = 500\Omega$	1	10	V/us
5	Open Loop Gain	A_{OL}	125°C	±28V	$R_L = 500\Omega, F = 10Hz$	91		dB
5	Common Mode Rejection	CMR	125°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	70		dB

BURN IN CIRCUIT



* These components are used to stabilize device due to poor high frequency characteristics of burn in board.

** Input signals are calculated to result in internal power dissipation of approximately 2.1W at case temperature = 125°C.